MOS FET

#### FM6K62010L

## **Panasonic**

### FM6K62010L

Silicon N-channel MOSFET(FET) Silicon epitaxial planar type(SBD)

For switching For DC-DC Converter

#### ■ Features

- Low drain-source ON resistance : RDS (on) typ. = 80 m $\Omega$  ( VGS = 4.0 V )
- Low drive voltage: 2.5 V drive
- Halogen-free / RoHS compliant (EU RoHS / UL-94 V-0 / MSL:Level 1 compliant)

■ Marking Symbol : Y5

Established: 2011-12-19

: 2013-10-18

Revised

#### ■ Packaging

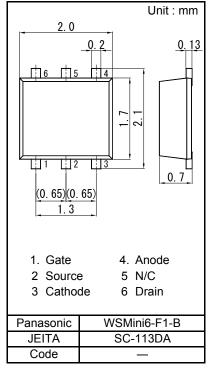
Embossed type (Thermo-compression sealing) 3 000 pcs / reel (standard)

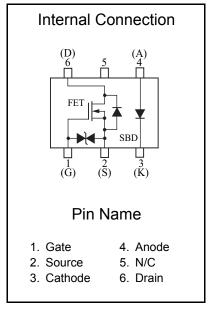
■ Absolute Maximum Ratings Ta = 25 °C

項目		Symbol	Rating	Unit	
FET	Drain to Source Voltage	VDS	20	V	
	Gate to Source Voltage	VGS	±10	V	
	Drain current	ID	2.0	Α	
	Drain Current (Pulsed)	IDp	12	Α	
	Channel temperature	Tch	125	°C	
SBD	Reverse voltage	VR	20	V	
	Forward current (Average)	IF(AV)	1.0	Α	
	Non-repetitive	IFSM	3.0	Α	
	Peak forward surge current *1	IFOIVI	3.0	, A	
	Junction temperature	Tj	125	°C	
Overall	Total power dissipation *2	PD	700	mW	
	Operating ambient temperature	Topr	-40 to + 85	°C	
	Storage temperature	Tstg	-55 to +125	°C	

Note: \*1 60 Hz sine wave 1 cycle (Non-repetitive peak current)

\*2 Measuring on ceramic substrate at 40 mm × 38 mm × 0.2 mm PD absolute maximum rating without a heat shink: 150 mW





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#### ■ Electrical Characteristics Ta = 25 °C ± 3 °C FET (N-ch.)

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Drain to Source Breakdown Voltage	VDSS	ID = 1.0 mA, VGS = 0	20			V
Zero Gate Voltage Drain Current	IDSS	VDS = 20 V, VGS = 0			1.0	μA
Gate-source Leakage Current	IGSS	VGS = ±8 V, VDS = 0			±10	μA
Gate-source Threshold Voltage	Vth	ID = 1.0 mA, VDS = 10 V	0.4	0.85	1.3	V
Drain-source On-State Resistance	RDS(on)1	ID = 1.0 A, VGS = 4.0 V		80	105	m()
	RDS(on)2	ID = 0.5 A, VGS = 2.5 V		100	150	mΩ
Forward transfer admittance	Yfs	ID = 1.0 A, VDS = 10 V	3.0			S
Input Capacitance	Ciss			280		
Output Capacitance	Coss	VDS = 10 V, VGS = 0, f = 1 MHz		18		pF
Reverse Transfer Capacitance	Crss			17		
Turn-on delay time *1	td(on)	VDD = 10 V, VGS = 0 V to 4 V		5		no
Rise time *1	tr	ID = 1.0 A		8		ns
Turn-off delay time *1	td(off)	VDD = 10 V, VGS = 4 V to 0 V		20		20
Fall time *1	tf	ID = 1.0 A		18		ns

Note: 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 Measuring methods for transistors.

#### SBD

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Forward voltage	VF1	IF = 800 mA			0.47	V
Forward voitage	VF2	IF = 1.0 A			0.52	V
Reverse current	IR	VR = 20 V			80	μA

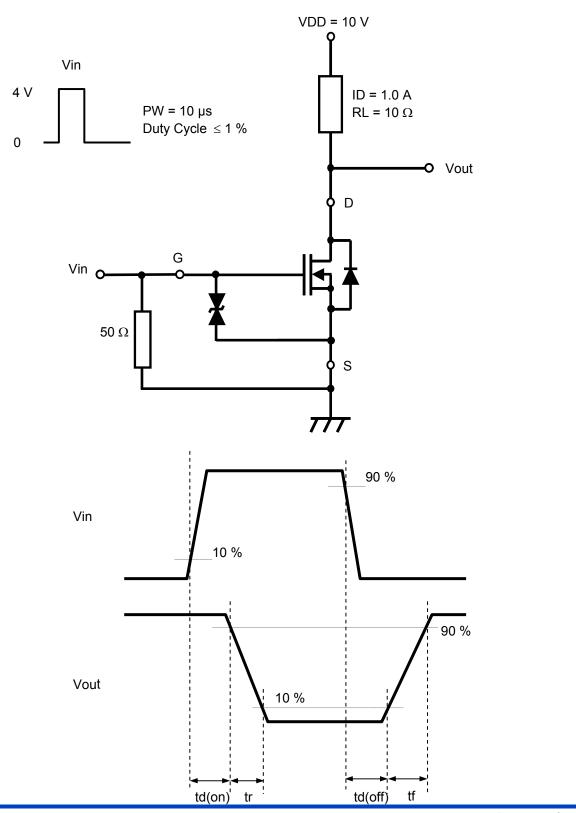
Note: Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7031 Measuring methods for diodes.

<sup>2. \*1</sup> Turn-on, Turn-off measurement circuit

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\*1 Turn-on, Turn-off measurement circuit



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## Technical Data (reference)

VGS = 4.0V

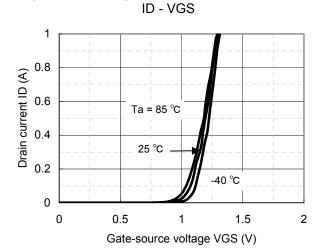
2
VGS = 4.0V

2.5 V

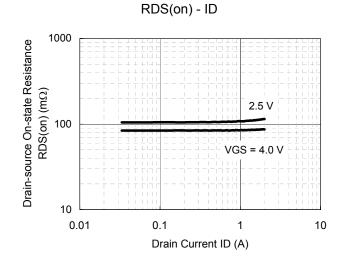
1.5 V

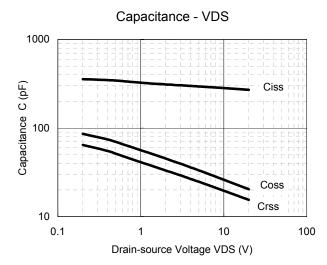
0
0
0
0.1
0.2
0.3

Drain-source voltage VDS (V)



VDS - VGS 0.6 0.5 A Drain-source Voltage VDS (V) 0.5 1.0 A 0.4 ID = 2.0 A 0.3 0.2 0.1 0 0 1 3 5 6 Gate-source Voltage VGS (V)

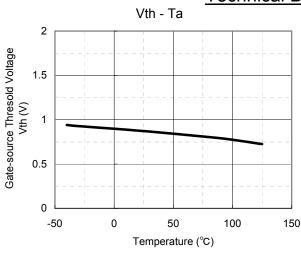


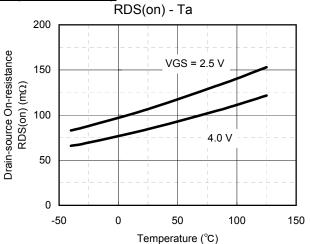


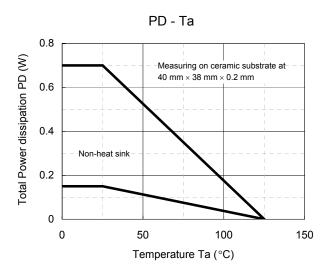
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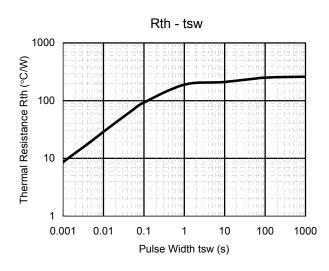
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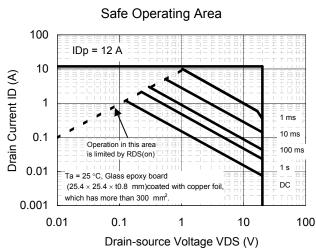
### Technical Data (reference)









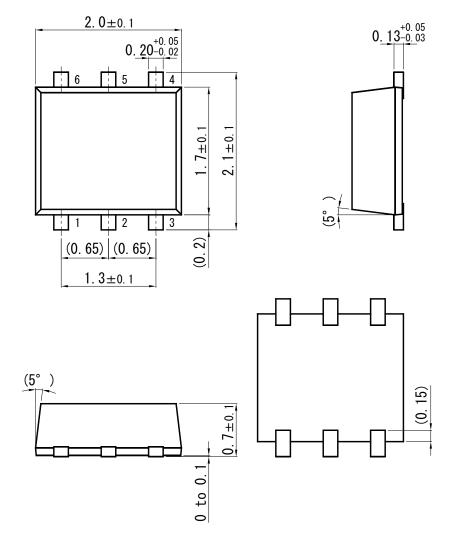


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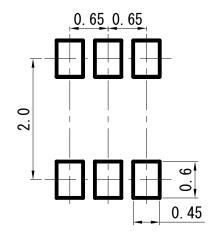
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## WSMini6-F1-B

Unit: mm



#### ■ Land Pattern (Reference) (Unit: mm)



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